



international

reliability physics symposium

NEWS RELEASE

International Reliability Physics Symposium (IRPS) expands offerings

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IRPS 2003 to Conduct Reliability Year In Review

DALLAS, Texas – February 12, 2003 – The 2003 International Reliability Physics Symposium (IRPS), which promotes the latest developments in the reliability and performance of integrated circuits and microelectronic assemblies, returns this year with a new session: the Reliability Year in Review seminar. This event is in addition to the technical seminars, featuring over 120 papers and posters, the 2-day tutorial series, workshops, poster session and equipment exhibition. IRPS 2003 will be held from March 30 through April 4, 2003 at the Hyatt Regency Hotel in Dallas, Texas.

Reliability Year in Review: New to IRPS this year, a half-day Reliability-Year-In-Review seminar will be held on Friday, April 4. Industry experts will highlight top papers in high-k dielectrics, Cu & low-k, nonvolatile memories and ESD. There is a separate nominal charge for this seminar that is separate from that of the IRPS conference. Registration is available online at www.irps.org/reg.htm.

Discount Hotel Reservations: If you are considering attending IRPS 2003 you are encouraged to reserve a hotel room before the reservations deadline to assure the room discount. The deadline is February 27 and demand is high. There is no penalty for cancellation prior to 24 hours. Hotel and car reservation information is also available online at www.irps.org/reg.htm.

Tutorials: As a continuation of the comprehensive symposium program, IRPS 2003 will include two intensive days of tutorials. The symposium will offer in-depth sessions covering a broad range of topics for industry veterans and newcomers. Tutorials scheduled for IRPS 2003 include:

High-k and Ultra-thin Dielectric Reliability
Copper / low-k integration and reliability challenges
Reinventing CMOS: Physics Reliability and The Roadmap
Introduction to Reliability, Introduction to WLR, Plastic Encapsulated Microcircuits for Harsh Environments, ESD Basics, Testing and Failure, NBTI SER Program, Product Reliability, Failure Analysis

The complete tutorial schedule for IRPS 2003, along with times, locations and links to the tutorial abstracts, is available online at www.irps.org/tutorials.

Workshop Sessions: IRPS 2003 will host its traditional workshops on Wednesday, April 2. These workshops provide attendees the opportunity to interact with recognized industry experts on evolving-technology reliability issues. Admission into IRPS workshops is included with conference registration.

Equipment Exhibition: Unique within the physics symposium circuit, IRPS 2003 will hold a technically oriented hands-on forum that will allow attendees to test new equipment. This program will be presented from Monday, March 31 through Thursday, April 3, with attendance open to the public Tuesday through Thursday.

A list of exhibitors to date registered to attend IRPS 2003 is available online at www.irps.org/exhibits/exhibitor_info.htm.

Poster Session

On Tuesday, April 1, IRPS will host more than 120 technical papers and posters including new sessions in high-k dielectrics, BEOL dielectrics (including low-k), SiGe reliability, SER, latch-up and circuit reliability. This is a unique opportunity to ask questions to all the IRPS authors.

About IRPS

For the past 40 years, IRPS has been one of the leading meetings for engineers in the area of electronic component reliability. IRPS promotes the comprehension of reliability and performance of integrated circuits and microelectronic assemblies through an improved understanding of failure mechanisms in the user's environment. Originally started in the early 1960's by the military and aerospace community, IRPS is now sponsored by IEEE Reliability Society and IEEE Electron Devices Society. All accepted IRPS papers will appear in the symposium proceedings publication, as well as on the Virtual IRPS DVD-ROM, which is available now for the previous 2002 IRPS.

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For further information, please visit the IRPS web site at www.irps.org or contact:

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